Supporting Information

Poly(3,4-ethylenedioxyselenophene): Effect of Solvent and Electrolyte on Electrodeposition, Optoelectronic and Electrochromic Properties

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SolventDielectric constant (ε)Viscosity (mPa s)Density(g/cm⁻³)Acetonitrile
(MeCN)37.500.340.79Propylene66.142.51.20

Table S1. Dielectric constant and viscosity of solvents at 25°C1

carbonate (PC)



Figure S1. Plots of cathodic and anodic peak current densities versus scan rates of PEDOS films prepared in different solvent-electrolyte medium a) TBAClO₄/MeCN, b) TBAPF₆/MeCN, c) TBABF₄/MeCN, d) TBAClO₄/PC, e) TBAPF₆/PC and f) TBABF₄/PC.



Figure S2. UV-vis absorption spectra of EDOS in acetonitrile and propylene carbonate.



Figure S3. Normalized UV-vis-NIR spectra of PEDOS films a) MeCN and b) PC in neutral states (-0.9 V) recorded in same solvent-electrolyte media as used for electropolymerization.





Figure S4. Normalized UV-vis-NIR spectra of PEDOS films prepared using a) TBAClO₄ and b) TBAPF₆ c) TBABF₄ in neutral states (-0.9 V) recorded in solvents MeCN and PC.





Figure S5. SEM images of PEDOS films prepared on ITO coated glass using repetitive cyclic voltammetry in different solvent-electrolyte media a) TBAClO₄/MeCN, b) TBAPF₆/MeCN, c) TBABF₄/MeCN d) TBAClO₄/PC e) TBAPF₆/PC f) TBABF₄/PC at scan rate of 100 mV/s. Magnification: 10000 and 20000 x. Concentration of supporting electrolyte is 0.1 M.

Reference

^{1.} S. Ming, Z. Feng, D. Mo, Z. Wang, K. Lin, B. Lu and J. Xu, *Phys.Chem. Chem. Phys.*, 2016, **18**, 5129-5138.